5th International Conference on Surface Metrology



4 – 7 April 2016 – PUT Campus Poznan, POLAND



Call for Papers





Surfaces cover everything

Submission from all fields involving the measurement and analysis of surface topographies including:

archeology, art conservation, anthropology, biology, biomedical engineering, chemistry, civil engineering, food science, forensics, geodetics, geology, material science, mechanical engineering, manufacturing, metrology, nanotechnology, physics, tribology...

Conference will be co-located with the exhibition of metrology equipment and software

Contact: icsm2016@put.poznan.pl Website: www.icsm2016.put.poznan.pl

Conference fees:

Early / Late

- Faculty & Industry: 450 / 550 Euro
- Student: 250 / 350 Euro

Early registration fee until 31 Jan 2016

Important dates:

- 7 Dec 2015 Abstracts (max. 1 page)
- 11 Jan 2016 Acceptance of Abstracts
- 15 Feb 2016 Full Paper
- 4 Apr 2016 Beginning of Conference

Fee includes:

- participation in sessions,
- proceedings (pendrive),
- coffee breaks and refreshments.
- social events and gala dinner,
- conference lunches (3x).

Publications:

After the conference, the authors of selected papers will be asked to submit their work for review to scientific indexed journals

Chair:

Michal Wieczorowski, Professor, Poznan University of Technology, Poland

Co-chairs:

Christopher A. Brown, Professor, Worcester Polytechnic Institute, USA

Pawel Pawlus, Professor, Rzeszow University of Technology, Poland

Magdalena Diering, Dr.,

Poznan University of Technology, Poland